

**Search Notes****Application/Control No.**

10/815,909

**Applicant(s)/Patent under Reexamination**

SETO ET AL.

**Examiner**

Christopher B. Shin

**Art Unit**

2181

**SEARCHED**

Class	Subclass	Date	Examiner
710	52-57	11/1/2006	CS
370	229-236	11/1/2006	CS
370	464-468	11/1/2006	CS
710	29-38	6/18/2007	CS
710	52-57	6/18/2007	CS
710	71	6/18/2007	CS
710	306-313	6/18/2007	CS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
710	310,29,52	6/13/2008	CS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM for double patenting	11/1/2006	CS
EAST (USPGPUB, USOCR, USPAT, EPO, JPO, DERWENT, IBMTDB, USOCR)	11/1/2006	CS
EAST (USPGPUB, USOCR, USPAT, EPO, JPO, DERWNET, IBMTDB)	6/18/2007	CS
PLUS	6/18/2007	CS
UPDATE search	6/13/2008	CS